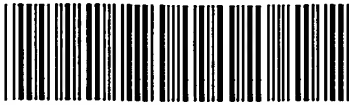


Search Notes

Application/Control No.

10/759,630

Examiner

Hae M. Hyeon

Applicant(s)/Patent under
Reexamination

BOEMMEL ET AL.

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
439	492	4/65	hmh
439	493		
439	495		
439	499		
439	714		
439	710		
439	590		
439	596		
439	937		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR